12500 TI Boulevard, MS 8640, Dallas, Texas 75243

PCN# 20240603002.2
Qualification of RFAB as an additional Fab site option for select ABCD6 devices
Change Notification / Sample Request

Date: June 04, 2024
To: MOUSER PCN

Dear Customer:

This is an announcement of a change to a device that is currently offered by Texas Instruments. The details of this change are on the following pages.

Texas Instruments requires acknowledgement of receipt of this notification within **30** days of the date of this notice. Lack of acknowledgement of this notice within 30 days constitutes acceptance of the change. If samples or additional data are required, requests must be received within **30 days** of this notification.

The changes discussed within this PCN will not take effect any earlier than the proposed first ship date on Page 3 of this notification, unless customer agreement has been reached on an earlier implementation of the change.

This notice does not change the end-of-life status of any product. Should product affected be on a previously issued product withdrawal/discontinuance notice, this notification does not extend the life of that product or change the life time buy offering/discontinuance plan.

For questions regarding this notice or to provide acknowledgement of this PCN, you may contact your local Field Sales Representative or the Change Management team.

For sample requests or sample related questions, contact your local Field Sales Representative.

Sincerely,

Change Management Team
SC Business Services

20240603002.2
Attachment: 1

Products Affected:

The devices listed on this page are a subset of the complete list of affected devices. According to our records, you have recently purchased these devices. The corresponding customer part number is also listed, if available.

DEVICE	CUSTOMER PART NUMBER
LM5145QRGYRQ1	NULL
LM5146QRGYRQ1	NULL
LM5146QRGYTQ1	NULL

Technical details of this Product Change follow on the next page(s).

PCN Number:	20240603002.2	PCN Date:	June 04, 2024
Title:	Qualification of RFAB as an additional Fab site option for select ABCD6 devices		
Customer Contact:	Change Management team	**Dept:**	Quality Services
Proposed 1st Ship Date:	December 01, 2024	**Sample requests accepted until:**	July 04, 2024*

***Sample requests received after July 04, 2024 will not be supported.**

Change Type:

☐	Assembly Site	☐	Design	☐	Wafer Bump Material
☐	Assembly Process	☐	Data Sheet	☐	Wafer Bump Process
☐	Assembly Materials	☐	Part number change	☒	Wafer Fab Site
☐	Mechanical Specification	☐	Test Site	☒	Wafer Fab Material
☒	Packing/Shipping/Labeling	☐	Test Process	☐	Wafer Fab Process

PCN Details

Description of Change:

Texas Instruments is pleased to announce the qualification of its RFAB fabrication facility as an additional Wafer Fab source for the selected devices listed in the "Product Affected" section.

Current Fab Site			Additional Fab Site		
Fab Site	**Process**	**Wafer Diameter**	**Fab Site**	**Process**	**Wafer Diameter**
MAINEFAB	ABCD6	200 mm	RFAB	ABCD6	300 mm

Qual details are provided in the Qual Data Section.

Reason for Change:

Continuity of Supply

Anticipated impact on Form, Fit, Function, Quality or Reliability (positive / negative):

None

Changes to product identification resulting from this PCN:

Fab Site Information:

Chip Site	Chip Site Origin Code (20L)	Chip Site Country Code (21L)	Chip Site City
MAINEFAB	CUA	USA	South Portland
RFAB	**RFB**	**USA**	**Richardson**

Sample product shipping label (not actual product label)

Product Affected:

LM5145QRGYRQ1	LM5146QRGYRQ1	LM5146QRGYTQ1

Automotive change Qualification Summary
(As per AEC-Q100 Rev. H and JEDEC Guidelines)

LM514xQRGY family: Addition of RFAB wafer fab into CDAT and UTL assembly sites
Approve Date 11-March-2024

Product Attributes

Attributes	Qual Device: CDAT LM5146QRGYRQ1	Qual Device: UTL1 LM5146QRGYRQ1	QBS Process Reference (Group B tests): LM5141QRGERQ1	QBS Package Reference: CDAT LM5143QRHARQ1	QBS Package Reference: UTL1 LM5146QRGYTQ1	QBS Package Reference: LM5146QRGYTQ1
Automotive Grade Level	Grade 1	Grade 1	Grade 1	Grade 1	Grade 1	Grade 1
Operating Temp Range (C)	-40 to 125	-40 to 125	-40 to 125	-40 to 125	-40 to 125	-40 to 125
Product Function	Power Management	Power Management	Power Management	Power Management	Power Management	Power Management
Wafer Fab Supplier	RFAB	RFAB	RFAB	RFAB	MAINEFAB	RFAB
Assembly Site	CDAT	UTL1	UTL1	CDAT	UTL1	CDAT
Package Group	QFN	QFN	QFN	QFN	QFN	QFN
Package Designator	RGY	RGY	RGE	RHA	RGY	RGY
Pin Count	20	20	24	40	20	24

- QBS: Qual By Similarity

Qualification Results

Data Displayed as: Number of lots / Total sample size / Total failed

Type	#	Test Spec	Min Lot Qty	SS / Lot	Test Name	Condition	Duration	Qual Device: CDAT LM5146QRGYRQ1	Qual Device: UTL1 LM5146QRGYRQ1	QBS Process Reference (Group B tests): LM5141QRGERQ1	QBS Package Reference: CDAT LM5143QRHARQ1	QBS Package Reference: UTL1 LM5146QRGYTQ1	QBS Package Reference: LM5146QRGYTQ1
Test Group A - Accelerated Environment Stress Tests													
Type	**#**	**Test Spec**	**Min Lot Qty**	**SS / Lot**	**Test Name**	**Condition**	**Duration**	**Qual Device: CDAT** LM5146QRGYRQ1	**Qual Device: UTL1** LM5146QRGYRQ1	**QBS Process Reference (Group B tests):** LM5141QRGERQ1	**QBS Package Reference: CDAT** LM5143QRHARQ1	**QBS Package Reference: UTL1** LM5146QRGYTQ1	**QBS Package Reference:** LM5146QRGYTQ1
PC	A1	JEDEC J-STD-020 JESD22-A113	3	77	Preconditioning	MSL2 260C	-	1/77/0	QBS		-	3/693/0	3/231/0
PC	A1	JEDEC J-STD-020 JESD22-A113	3	77	Preconditioning	MSL3 260C	-	QBS	QBS		3/693/0	-	-
HAST	A2	JEDEC JESD22-A110	3	77	Biased HAST	130C/85%RH	96 Hours	QBS	QBS		3/231/0	3/231/0	3/231/0
AC/UHAST	A3	JEDEC JESD22-A102/JEDEC JESD22-A118	3	77	Unbiased HAST	130C/85%RH	96 Hours	QBS	QBS		3/231/0	3/231/0	3/231/0
TC	A4	JEDEC JESD22-A104 and Appendix 3	3	77	Temperature Cycle	-65C/150C	500 Cycles	1/77/0	QBS		3/231/0	3/135/0	3/231/0
TC-BP	A4	MIL-STD883 Method 2011	1	5	Post Temp Cycle Bond Pull	-	-	1/5/0	QBS		1/5/0	1/5/0	-
HTSL	A6	JEDEC JESD22-A103	1	45	High Temperature Storage Life	150C	1000 Hours	QBS	QBS		3/135/0	3/135/0	3/135/0
Test Group B - Accelerated Lifetime Simulation Tests													
HTOL	B1	JEDEC JESD22-A108	3	77	Life Test	125C	1000 Hours	1/77/0	QBS	3/231/0	-		-
ELFR	B2	AEC Q100-008	3	800	Early Life Failure Rate	125C	48 Hours	QBS	QBS	3/2400/0	-		-
Test Group C - Package Assembly Integrity Tests													
WBS	C1	AEC Q100-001	1	30	Wire Bond Shear	Minimum of 5 devices, 30 wires Cpk>1.67	Wires	1/30/0	1/30/0		3/90/0	3/90/0	
WBP	C2	MIL-STD883 Method 2011	1	30	Wire Bond Pull	Minimum of 5 devices, 30 wires Cpk>1.67	Wires	1/30/0	1/30/0		3/90/0	3/90/0	
SD	C3	JEDEC J-STD-002	1	15	PB-Free Solderability	>95% Lead Coverage	-	-	-		1/15/0	1/15/0	-
PD	C4	JEDEC JESD22-B100 and B108	3	10	Physical Dimensions	Cpk>1.67	-					3/30/0	3/30/0

Type	#	Test Spec	Min Lot Qty	SS / Lot	Test Name	Condition	Duration	Qual Device: CDAT LM5146QRGYRQ1	Qual Device: UTL1 LM5146QRGYRQ1	QBS Process Reference (Group B tests): LM5141QRGERQ1	QBS Package Reference: CDAT LM5143QRHARQ1	QBS Package Reference: UTL1 LM5146QRGYTQ1	QBS Package Reference: LM5146QRGYTQ1
Test Group D - Die Fabrication Reliability Tests													
EM	D1	JESD61	-	-	Electromigration	-	-	Completed Per Process Technology Requirements	Completed Per Process Technology Requirements	Completed Per Process Technology Requirements	Completed Per Process Technology Requirements	Completed Per Process Technology Requirements	Completed Per Process Technology Requirements
TDDB	D2	JESD35	-	-	Time Dependent Dielectric Breakdown	-	-	Completed Per Process Technology Requirements	Completed Per Process Technology Requirements	Completed Per Process Technology Requirements	Completed Per Process Technology Requirements	Completed Per Process Technology Requirements	Completed Per Process Technology Requirements
HCI	D3	JESD60 & 28	-	-	Hot Carrier Injection	-	-	Completed Per Process Technology Requirements	Completed Per Process Technology Requirements	Completed Per Process Technology Requirements	Completed Per Process Technology Requirements	Completed Per Process Technology Requirements	Completed Per Process Technology Requirements
BTI	D4	-	-	-	Bias Temperature Instability	-	-	Completed Per Process Technology Requirements	Completed Per Process Technology Requirements	Completed Per Process Technology Requirements	Completed Per Process Technology Requirements	Completed Per Process Technology Requirements	Completed Per Process Technology Requirements
SM	D5	-	-	-	Stress Migration	-	-	Completed Per Process Technology Requirements	Completed Per Process Technology Requirements	Completed Per Process Technology Requirements	Completed Per Process Technology Requirements	Completed Per Process Technology Requirements	Completed Per Process Technology Requirements
Test Group E - Electrical Verification Tests													
ESD	E2	AEC Q100-002	1	3	ESD HBM	-	2000 Volts	1/3/0	Device specific data				
ESD	E3	AEC Q100-011	1	3	ESD CDM	-	500 Volts	1/3/0	Device specific data				
LU	E4	AEC Q100-004	1	6	Latch-Up	Per AEC Q100-004	-	1/6/0	Device specific data				
ED	E5	AEC Q100-009	3	30	Electrical Distributions	Cpk>1.67 Room, hot, and cold	-	3/30/0	Device specific data				
Additional Tests													

- Preconditioning was performed for Autoclave, Unbiased HAST, THB/Biased HAST, Temperature Cycle, Thermal Shock, and HTSL, as applicable
- The following are equivalent HTOL options based on an activation energy of 0.7eV : 125C/1k Hours, 140C/480 Hours, 150C/300 Hours, and 155C/240 Hours
- The following are equivalent HTSL options based on an activation energy of 0.7eV : 150C/1k Hours, and 170C/420 Hours
- The following are equivalent Temp Cycle options per JESD47 : -55C/125C/700 Cycles and -65C/150C/500 Cycles

Ambient Operating Temperature by Automotive Grade Level:

- Grade 0 (or E): -40C to +150C
- Grade 1 (or Q): -40C to +125C
- Grade 2 (or T): -40C to +105C
- Grade 3 (or I) : -40C to +85C

E1 (TEST): Electrical test temperatures of Qual samples (High temperature according to Grade level):

- Room/Hot/Cold : HTOL, ED
- Room/Hot : THB / HAST, TC / PTC, HTSL, ELFR, ESD & LU
- Room : AC/uHAST

Quality and Environmental data is available at TI's external Web site: http://www.ti.com/

TI Qualification ID: R-CHG-2304-014

Affected ZVEI IDs: SEM-PW-13, SEM-PW-02

For questions regarding this notice, e-mails can be sent to the Change Management team or your local Field Sales Representative.

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